



Overcoming Challenges in 2D-Nanopositioning Systems MOCRAF 2023: Overcoming Existing System Limits

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2023-10-08 MOCRAF 2023 - Overcoming Challenges in 2D-Nanopositioning Systems





Introduction & Setup





Introduction

The Nanoscopium beamline (SOLEIL)

Offer 2D-nano-imaging services :

- Sample Sizes: < 100x100 μm
- Continuous scans (aka Flyscan)
- Imaging resolutions: 50 nm



2D-nano-Scanner Problems

- Degrading/unreliable positioning/movement performance
 - Short term (< 30 min) → Long term (Several Hours)

-Strange limit switch activation (usually after some use)

Imaging resolutions (today): ~150 nm

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Control Architecture

Gallil Controller

- ControlBox (Point-to-Point, open-loop)

Driver/Controller

Npoint LC-403 (Closed-loop with PID)

Piezo, stacked design (100x100x100 µm range)

Strain gauges sensors for positioning

- Pulse-Dir (PFM)
- AquadB interface

Actuators & Sensors

Npoint NPCube



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Black box





Scan Trajectory Type

« Fast » 2D-raster scans

- Continuos scans on **X-axis** (Flyscan) (deca-µm range with deca-µm speeds)
- Step-scans on Z-axis
 (deca-µm range with deca-nanometric steps)
- While holding position on Y-axis



Example (2D- raster flyscan)



Actions

- External Metrology Frame
 - Interferometers (Attocube)
 - Rigid Aluminium
 - Mechanical adjustments (Piezo stage, interferometer sensors, mirrors, etc)

- Several interventions (in beamline):
 - PID retuning (Npoint LC-403)
 - Sensor recalibrations (Npoint LC-403)
 - Positioning tests
 - Positioning (step-responses)
 - 2D-flyscans
 - Stability tests (interferometer vs encoder)
 - During/after system startup (ex: heating effects)
 - During/after 2D-scans







- External Metrology Frame
 - Interferometers (Attocube)
 - Rigid Aluminium
- Several interventions on be (Usually half-day → full-date)
 - PID tuning (Npoint LC-40)
 - Mechanical adjustments (sensors, mirrors, etc)
 - Sensor recalibrations (Np)
 - Positioning tests
 - Positioning (step-respon
 - 2D-flyscans
 - Stability tests (interferometerom)
 - During/after system star
 - During/after 2D-scans

Have yielded **mixed results**. And when positive, usually only temporary or just over very short term scans.





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- System (Npoint) was installed in the Electronics laboratory for long-term testing.
 - With Metrology frame + interferometers
 - Without PandaBox
- Temperature sensor installed on metrology frame
- SOLEIL ControlBox was eventually replaced with high-performing Delta Tau/Omron Powerbrick Controller
- Executed many automated, long-term (24h), and large (~< 90x90 μm) XZ- scans in various configurations
- All scans are monitored using interferometers on the XZ-axes





Open-loop Tests (back-to-back scans during ~23 h)

- First scan vs Last scan
 - 2D-scan has "shifted" several µm + activated negative limit switches for X and Z.

X- axis « drifted » 5 µm during 14h of constant use!





→ Errors of up to ~350 nm/h



« Slow drift » problem stems from control pulses lost over time. Only a few pulses lost every 1 million pulses → Enough to drift several µm over hours of constant use.

Solution:

Close the loop (PID) at the Powerbrickcontroller level (provided that the encoder is fully functional).







Closed-loop Tests (one 2D-scan, ~7.14min)

In-Lab Tests









Z- movements are supposed to hold a « staircase » -shape. → There are motion errors/crosstalk between axes X and Z.



Solution:

Calculate **repeteable crosstalk error** from long-term data and **apply active cross-axis compensation** in the Powerbrick Controller. → errors of up to ~500 nm





Key Actions

Positional XZ- drifts larger than 750 nm evident (the Z-lines «blur»).

Temperature seems to have a high linear correlation.

Measurement errors of up to ~180 nm/0.1°C

Possible source of positional drifts measurements: Thermal dilations of the metrology frame









What did we learn?

- The SOLEIL Controller (Delta Tau) needs to be in closed-loop (eliminate position drift errors of up to ~350 nm/h or more)
- We need to actively correct for XZ-crosstalk errors.
 (eliminate repeatable errors of up to ~500 nm)
- Temperature differences has non-negligible impact on our metrology frame, causing measurements errors (Measurement errors of up to ~180 nm/0.1°C)





Beamline Tests

(With Metrology Frame, not beam)





Closed-loop Tests (One 2D-scan, ~7.14min)

Beamline Tests

8





Closed-loop Tests (One 2D-scan, ~7.14min)

Beamline Tests

Z-movements are exhibiting a nice « staircase » -shape.





Closed-loop Tests (Long-term 2D-scans, ~8h)

Beamline Tests

Continuous 2d-snake scan (~ 8h, ~ 68 continuous scan)





Beamline Tests

« Spread » around Z during the 8h scan: ~< 100 nm

However (during this 8h period, marked red), there are temperature fluctuations (+/- 0.1°C), indicating possible measurement errors from metrology frame.



Actual results may be better (temperature sensor + metrology frame limitation). Need to test with beam to verify !!!